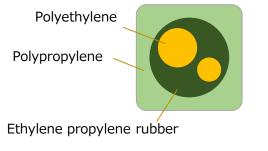
AFM Application Data Sheet



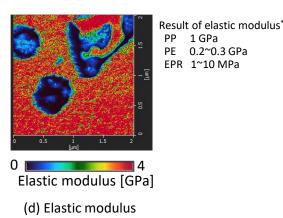
Mechanical-Property Mapping of Automotive Plastic Materials

(e) Deformation

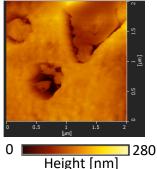
Using SIS-ACCESS



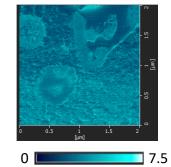
(a) Structure of ternary polymer blend



*note: SIS-Quantimech (Optional) is necessary for analysis of elastic modulus image.



(b) Topographic

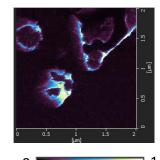


Deformation [nm] Adhesion [nN] (f) Adhesion

Fig.1 Mechanical-property mapping of ternary polymer blend

Differential [nm]

(c) Differential



Dissipation [arb.] (g) Dissipation

Model AFM5300E

SHFFT No. 019



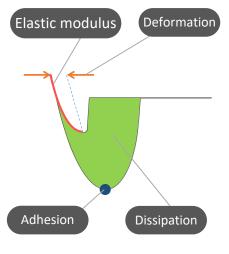


Fig. 2 How to analyze force curve

SIS-ACCESS extends the capabilities of Sampling Intelligent Scan (SIS) and enables the simultaneous acquisition of up to 8 data channels on surface topography and various physical properties (both mechanical and electrical properties). By measuring both force curves at each pixel and retracting the probe from the sample when moving between pixels, the physical property mapping image can stably obtained without damaging the sample even with soft materials such as polymer or rubber.

Fig. 1 shows the results from using SIS-ACCESS on a plastic material that is utilized in the auto industry. As shown in Fig. 2, multiple physical properties can be derived from the force curve measured at each pixel, proving that ethylene propylene rubber (EPR) is much softer than the polypropylene (PP) matrix, and corresponding deformation, adhesion, and dissipation signals in EPR regions are significantly higher than those in PP matrix . In addition, the elastic modulus of polyethylene (PE) is intermediate between PP and EPR. Based on these observations, the three components can be differentiated and their compositional mapping at sub-micrometer scale can be achieved.

*Data provided by Mr. T. Nakashima and Dr. Y. Namai of Mitsui Chemical Analysis & Consulting Service, Inc.

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Measurement of Mechanical-Property Mapping of Automotive Plastic Materials Using SIS-ACCESS



Recommended configuration	Remarks
Environment-Control Unit AFM5300E	
Probe Station AFM5000 II	
SIS-ACCESS	
SIS-QuantiMech	
Cantilever : SI-DF3P2	



AFM5300E